捷多邦,专业PCB打样ISN5444V4175A出SN74LV175A QUADRUPLE D-TYPE FLIP-FLOPS WITH CLEAR

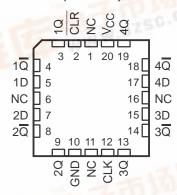
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- EPIC™ (Enhanced-Performance Implanted CMOS) Process
- Typical V_{OLP} (Output Ground Bounce)
 <0.8 V at V_{CC} = 3.3 V, T_A = 25°C
- Typical V_{OHV} (Output V_{OH} Undershoot)
 >2.3 V at V_{CC} = 3.3 V, T_A = 25°C
- 2-V to 5.5-V V_{CC} Operation
- Support Mixed-Mode Voltage Operation on All Ports
- Contain Four Flip-Flops With Double-Rail Outputs
- Applications Include:
 - Buffer/Storage Registers
 - Shift Registers
 - Pattern Generators
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Package Options Include Plastic Small-Outline (D, NS), Shrink Small-Outline (DB), Thin Very Small-Outline (DGV), and Thin Shrink Small-Outline (PW) Packages, Ceramic Flat (W) Packages, Chip Carriers (FK), and DIPs (J)

SN54LV175A . . . J OR W PACKAGE SN74LV175A . . . D, DB, DGV, NS, OR PW PACKAGE (TOP VIEW)



SN54LV175A . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

description

The 'LV175A devices are quadruple D-type flip-flops designed for 2-V to 5.5-V V_{CC} operation.

These devices have a direct clear (CLR) input and feature complementary outputs from each flip-flop.

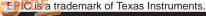
Information at the data (D) inputs meeting the setup time requirements is transferred to the outputs on the positive-going edge of the clock (CLK) pulse.

Clock triggering occurs at a particular voltage level and is not directly related to the transition time of the positive-going edge of CLK. When CLK is at either the high or low level, the D input has no effect at the output.

The SN54LV175A is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74LV175A is characterized for operation from –40°C to 85°C.



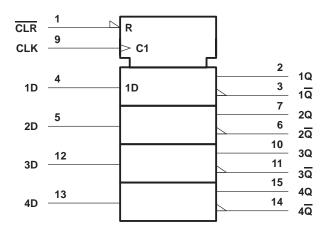
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FUNCTION TABLE (each flip-flop)

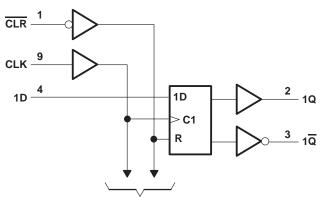
	•					
	INPUTS		OUTI	PUTS		
CLR	CLK	D	Q			
L	Х	Χ	L	Н		
Н	\uparrow	Н	Н	L		
Н	\uparrow	L	L	Н		
Н	L	Χ	Q ₀	\overline{Q}_0		

logic symbol†



 $[\]dagger$ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, DB, DGV, J, NS, PW, and W packages.

logic diagram (positive logic)



To Three Other Channels

Pin numbers shown are for the D, DB, DGV, J, NS, PW, and W packages.



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}		–0.5 V to 7 V
Input voltage range, V _I (see Note 1)		0.5 V to 7 V
Voltage range applied to any output in the high	h-impedance	
or power-off state, V _O (see Note 1)		–0.5 V to 7 V
Output voltage range, VO (see Notes 1 and 2))	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, I_{IK} ($V_I < 0$)		
Output clamp current, IOK (VO < 0 or VO > VO		
Continuous output current, I_O ($V_O = 0$ to V_{CC})		
Continuous current through V _{CC} or GND		
Package thermal impedance, θ _{JA} (see Note 3)		
, , , , , , , , , , , , , , , , , , , ,	DB package	
	DGV package	
	NS package	
	PW package	
Storage temperature range, T _{stg}		

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

- 2. This value is limited to 5.5 V maximum.
- 3. The package thermal impedance is calculated in accordance with JESD 51.



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recommended operating conditions (see Note 4)

			SN54L	V175A	SN74L	V175A	UNIT
			MIN	MAX	MIN	MAX	UNII
Vcc	Supply voltage		2	5.5	2	5.5	V
		V _{CC} = 2 V	1.5		1.5		
\ \ _{\\}	High-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	V _{CC} ×0.7		$V_{CC} \times 0.7$		V
VIH	nigri-iever iriput voitage	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$	V _{CC} ×0.7		$V_{CC} \times 0.7$		'
		V _{CC} = 4.5 V to 5.5 V	V _{CC} × 0.7		$V_{CC} \times 0.7$		
		V _{CC} = 2 V		0.5		0.5	
\ \/	Low-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		$V_{CC} \times 0.3$		$V_{CC} \times 0.3$	V
VIL	Low-level input voltage	$V_{CC} = 3 V \text{ to } 3.6 V$		$V_{CC} \times 0.3$		$V_{CC} \times 0.3$	'
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$		$V_{CC} \times 0.3$		$V_{CC} \times 0.3$	
VI	Input voltage		0	5.5	0	5.5	V
VO	Output voltage		0	V°CC	0	VCC	V
		V _{CC} = 2 V	Q	- 50		-50	μΑ
lou	High-level output current	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1	-2		-2	
ЮН	riigir-ieveroutput current	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$	3	-6		-6	mA
		V _{CC} = 4.5 V to 5.5 V	20	-12		-12	
		V _{CC} = 2 V	Q	50		50	μΑ
	Low-level output current	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		2		2	
lOL	Low-level output current	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$		6		6	mA
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$		12		12	
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0	200	0	200	
Δt/Δν	Input transition rise or fall rate	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$	0	100	0	100	ns/V
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	0	20	0	20	
TA	Operating free-air temperature		-55	125	-40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETER	TEST COMPITIONS	T .,	SN54LV175A	SN74LV175A	
PARAMETER	TEST CONDITIONS	Vcc	MIN TYP MA	K MIN TYP MAX	UNIT
	I _{OH} = -50 μA	2 V to 5.5 V	V _{CC} -0.1	V _{CC} -0.1	
Vari	$I_{OH} = -2 \text{ mA}$	2.3 V	2	2	\ _\
VOH	I _{OH} = -6 mA	3 V	2.48	2.48	ľ
	I _{OH} = -12 mA	4.5 V	3.8	3.8	
	I _{OL} = 50 μA	2 V to 5.5 V	0.	1 0.1	
\/	$I_{OL} = 2 \text{ mA}$	2.3 V	0.	4 0.4	l _v
VOL	$I_{OL} = 6 \text{ mA}$	3 V	0.4	0.44]
	I _{OL} = 12 mA	4.5 V	0.5	5 0.55	
lį	V _I = V _{CC} or GND	0 V to 5.5 V	±	1 ±1	μΑ
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V	2	0 20	μΑ
l _{off}	V_I or $V_O = 0$ to 5.5 V	0 V		5 5	μΑ
Ci	V _I = V _{CC} or GND	3.3 V	1.4	1.4	pF

timing requirements over recommended operating free-air temperature range, V_{CC} = 2.5 V \pm 0.2 V (unless otherwise noted) (see Figure 1)

			T _A = :	25°C	SN54L	/175A	SN74L	/175A	UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	UNII
	Pulse duration	CLR low	6		6		6		no
t _W	ruise duration	CLK high or low	6.5		7	10,01	7		ns
	0.1.1.1.011/1	Data	7		7.5	JIV.	7.5		
t _{su}	Setup time before CLK↑	CLR inactive	7		7.5		7.5		ns
th	Hold time, data after CLK↑		0.5		1		1		ns

timing requirements over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

			$T_A = 1$	25°C	SN54L	V175A	SN74L	/175A	UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	UNIT
	Dulas duration	CLR low	5		5		5		ns
t _W Pulse duration		CLK high or low	5		5	N,U	5		115
		Data	5		5	III	5		no
tsu	Setup time before CLK↑	CLR inactive	5		5	~	5		ns
t _h	Hold time, data after CLK↑		1		1		1		ns



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timing requirements over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

			$T_A = 2$	25°C	SN54L	/175A	SN74L\	√175A	UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	UNIT
	Dulgo duration	CLR low	5		5		5		no
t _W Pulse duration		CLK high or low	5		5	10,71	5		ns
		Data	4		4	, JIV	4		
t _{su}	Setup time before CLK↑	CLR inactive	5		5		5		ns
th	Hold time, data after CLK↑		1		1		1		ns

switching characteristics over recommended operating free-air temperature range, V_{CC} = 2.5 V \pm 0.2 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	LOAD	T,	Δ = 25°C	;	SN54L\	/175A	SN74L\	/175A	UNIT
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
f			C _L = 15 pF	50*	105*		45*		45		MHz
fmax			$C_{L} = 50 \text{ pF}$	40	80		35	100	35		IVITZ
	CLR	Any	C 15 pE		7.9*	16.6*	1*	20*	1	20	no
^t pd	CLK	Any	C _L = 15 pF		9.3*	18.8*	4*	22*	1	22	ns
	CLR	Any	C 50 pE		10.4	21.6	1	25.5	1	25.5	no
^t pd	CLK	Any	C _L = 50 pF		12	23.3	1	27	1	27	ns
tsk(o)			C _L = 50 pF			2				2	ns

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	LOAD	T,	Δ = 25°C	;	SN54L\	/175A	SN74L\	/175A	UNIT
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
			C _L = 15 pF	90*	155*		75*		75		MHz
fmax			C _L = 50 pF	50	120		45	10,01	45		IVIITZ
4 .	CLR	Any	C 15 pF		5.5*	10.1*	(1*)	12*	1	12	no
^t pd	CLK	Any	$C_L = 15 pF$		6.5*	11.5*	4*	13.5*	1	13.5	ns
4 .	CLR	Any	C 50 pF		7.4	13.6	1	15.5	1	15.5	no
^t pd	CLK	Any	C _L = 50 pF		8.4	15	1	17	1	17	ns
^t sk(o)		·	C _L = 50 pF			1.5				1.5	ns

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested.



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switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	LOAD	T,	_Δ = 25°C	;	SN54L\	/175A	SN74L	/175A	UNIT
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
£			C _L = 15 pF	150*	215*		125*		125		MHz
[†] max			C _L = 50 pF	85	165		75	J.M	75		IVITIZ
	CLR	Any	C. 15 pF		3.7*	6.4*	1*	7.5*	1	7.5	
^t pd	CLK	Any	C _L = 15 pF		4.6*	7.3*	4*	8.5*	1	8.5	ns
.	CLR	Any	C 50 pF		5.3	8.4	1	9.5	1	9.5	no
^t pd	CLK	Any	$C_L = 50 \text{ pF}$		6	9.3	1	10.5	1	10.5	ns
tsk(o)			C _L = 50 pF			1				1	ns

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested.

noise characteristics, V_{CC} = 3.3 V, C_L = 50 pF, T_A = 25°C (see Note 5)

	PARAMETER	SN	74LV175	iΑ	UNIT
	PARAMETER	MIN	TYP	MAX	UNIT
V _{OL(P)}	Quiet output, maximum dynamic V _{OL}		0.3	0.8	V
V _{OL(V)}	Quiet output, minimum dynamic VOL		-0.3	-0.8	V
V _{OH(V)}	Quiet output, minimum dynamic VOH		3		V
V _{IH(D)}	High-level dynamic input voltage	2.31			V
V _{IL(D)}	Low-level dynamic input voltage			0.99	V

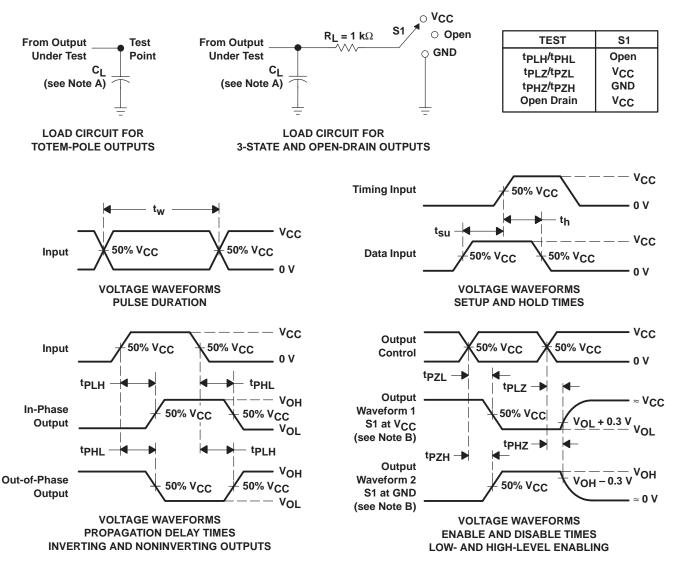
NOTE 5: Characteristics are for surface-mount packages only.

operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	VCC	TYP	UNIT
Card	Power dissination canacitance	C ₁ = 50 pF, f = 10 MHz	3.3 V	13.6	pF
Cbq	Power dissipation capacitance	CL = 50 pr, T = 10 MHZ	5 V	14.5	рі

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PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_I includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_Q = 50 \Omega$, $t_f \leq 3$ ns, $t_f \leq 3$ ns.
- D. The outputs are measured one at a time with one input transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tpHL and tpLH are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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